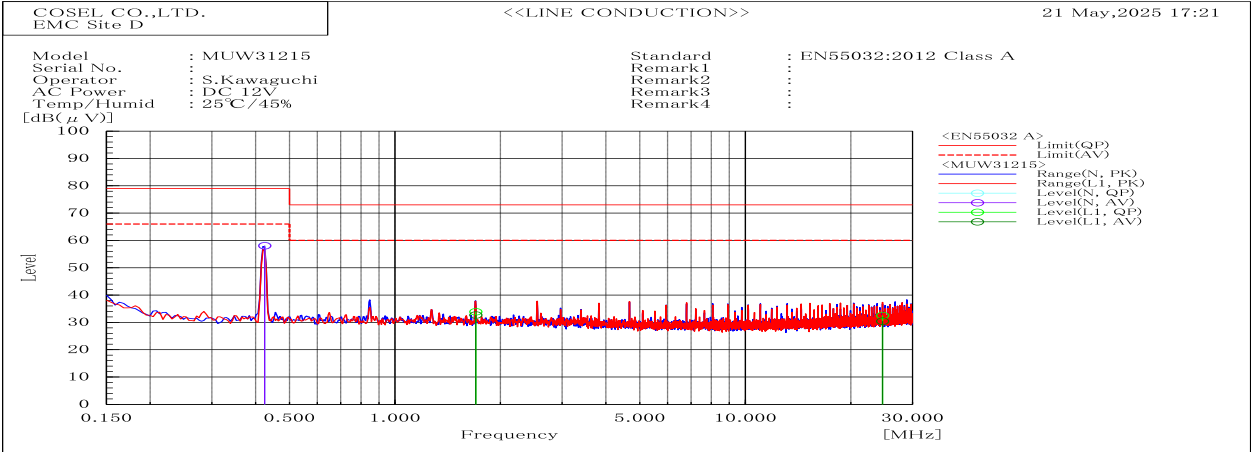
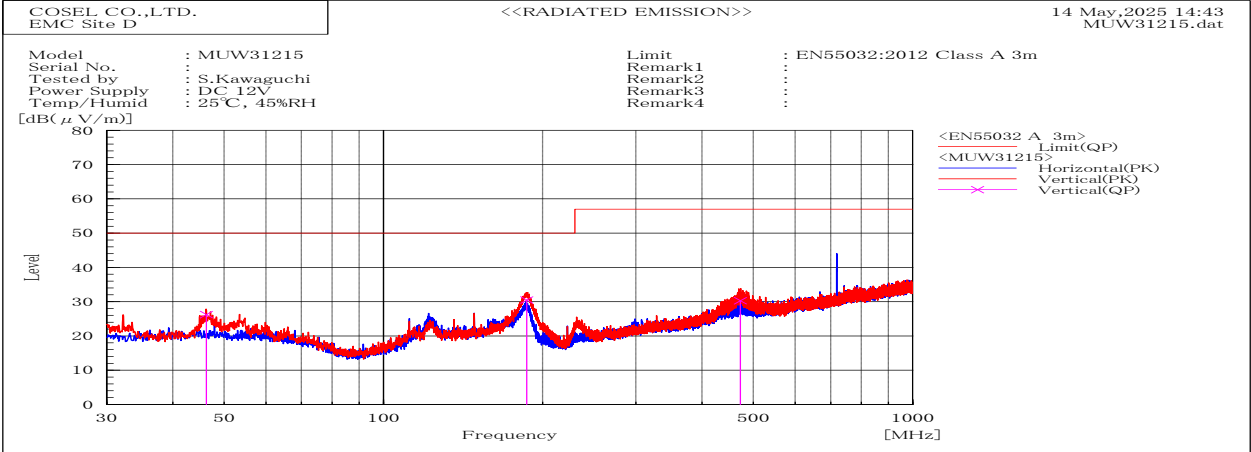


DATA SHEET		Date	21-May-25
Model	MUW31215	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



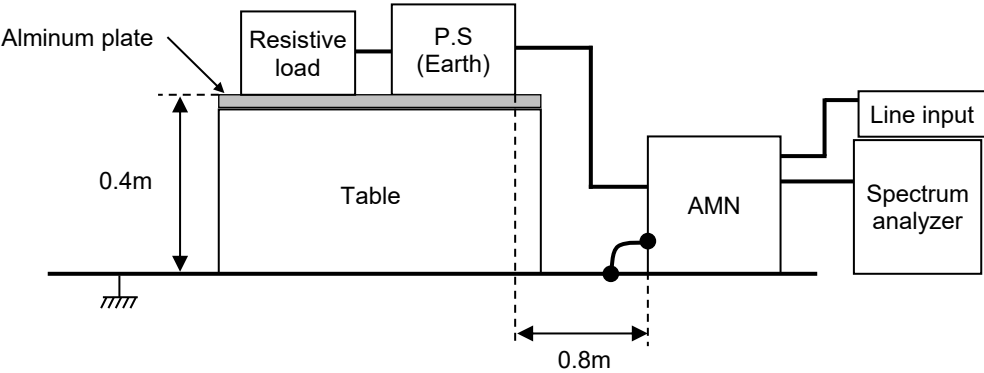
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.425	N	58.2	58	79	66	20.8	8	Pass	
1.7	L1	33.9	32.7	73	60	39.1	27.3	Pass	
24.637	L1	32.5	30.4	73	60	40.5	29.6	Pass	



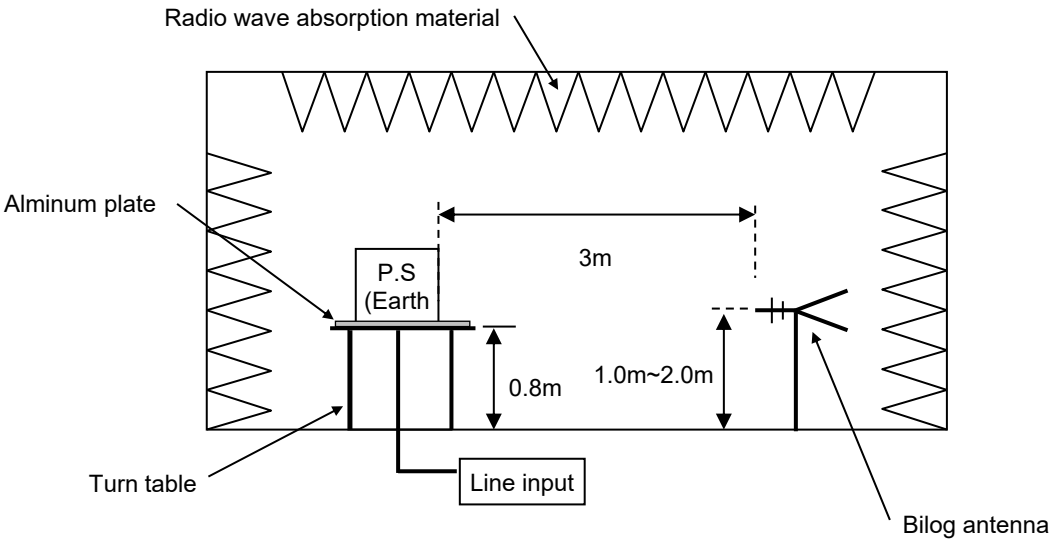
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
186.478	V	Stable	30.5	50	19.5	Pass	100	9.5	
46.293	V	Stable	26.2	50	23.8	Pass	100	185.8	
472.527	V	Stable	30.3	57	26.7	Pass	119.9	205.3	

DATA SHEET		Date	21-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

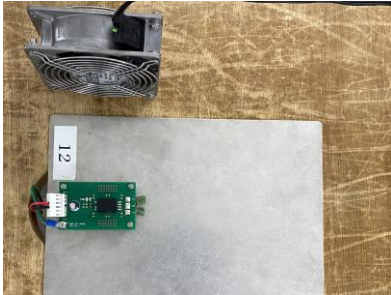
Test : EMI
Model Name: MUW3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

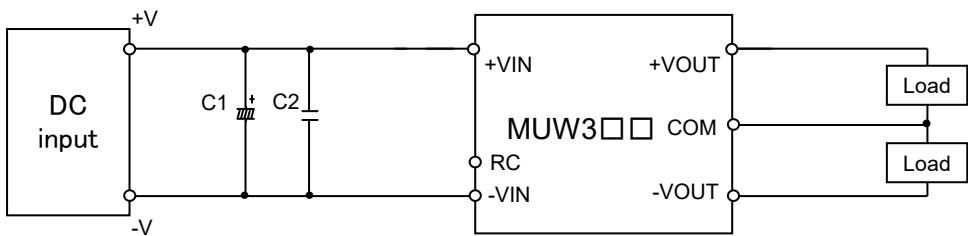


Fig.1 MUW305□, MUW312□, MUW324□ Testing circuitry

- | | | | |
|------|---------|-----------------|---|
| C1 : | MUW305□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW312□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW324□ | — | |
| C2 : | MUW305□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUW312□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUW324□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

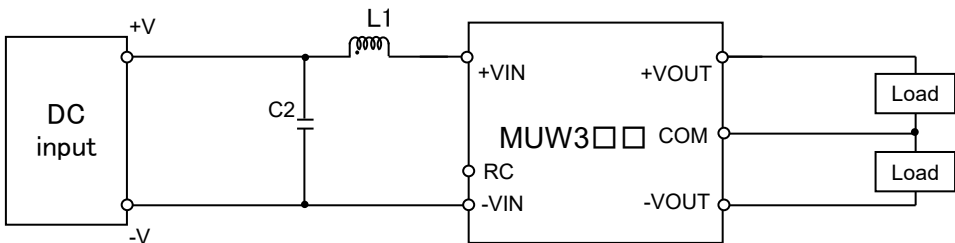


Fig.2 MUW348□ Testing circuitry

- | | | | |
|------|---------|------------------|--|
| C2 : | MUW348□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUW348□ | 520mA 15 μ H | Inductor (LQH32PN150MN0L MURATA MANUFACTURING) |